

Form PTO 1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT			ATTY DOCKET NO. 220152US0PCT		SERIAL NO. New US PCT application based on PCT/FR01/02189		
			APPLICANT Philippe GAUCHER				
			FILING DATE Herewith		GROUP		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>ILS</i>	AA	5 846 686	12/08/98	Akira KAMISAWA	<i>430</i>	<i>197</i>	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>ILS</i>	AO	0 431 999	06/12/91	EP	No		
<i>ILS</i>	AP	97 33310	09/12/97	WO	No		
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>ILS</i>	AW	N. TOHGE et al.: "Direct fine-pattering of PZT thin films using photosensitive gel films derived from chemically modified metal-alkoxides" JOURNAL OF MATERIALS SCIENCE. MATERIALS IN ELECTRONICS, vol. 10, no. 4, pages 273-277 06/99					
<i>ILS</i>	AX	R.W. SCHWARTZ et al.: "Effects of acetylacetone additions on PZT thin film processing" MATERIALS RESEARCH SOCIETY SYMPOSIUM PROCEEDINGS 1995					
<i>ILS</i>	AY	Y.T. KWON et al.: "Effect of sol-gel precursors on the grain structure of PZT thin films" MATERIALS RESEARCH BULLETIN, vol. 34, no. 5, pages 749-760 03/15/99					
	AZ				<input type="checkbox"/> Additional References sheet(s) attached		
Examiner	<i>K Sayar</i>			Date Considered <i>10/18/02</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							